Notice of References Cited Application/Control No. 10/510,302 Examiner Abiy Getachew Applicant(s)/Patent Under Reexamination VERWEG ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,440,452	08-1995	Kitahara, Akira	361/773
*	В	US-2005/0142917 A1	06-2005	Verweg et al.	439/212
*	С	US-2005/0237424 A1	10-2005	Weekamp et al.	348/373
*	D	US-6,486,412 B2	11-2002	Kato, Hiroki	174/260
*	Е	US-7,078,788 B2	07-2006	Vu et al.	257/668
*	F	US-7,067,356 B2	06-2006	Towle et al.	438/122
*	G	US-7,053,381 B2	05-2006	Shaw et al.	250/370.11
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q	•				
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	x	

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